



Royal Society of Chemistry Particle Characterisation Interest Group

Meeting – 4th April 2018 9am for a 9:30 start

RSC, Burlington House, Piccadilly, London W1J 0BA

Robust Particle Characterisation including International Standards

<http://www.rsc.org/events/detail/30847/robust-particle-characterisation-including-international-standards>.

Robustness and reliability of any type of measurement is an important facet of ensuring quality of products. Particle characterisation covers so many different sample types and techniques that ensuring that a quality driven approach to sampling and analysis as well as data presentation and understanding is vital to producing data that research and processes can rely on to make decisions.

The meeting will cover a wide range of issues including new equipment, reviews of procedures, equipment and instrument validation with particular reference to the wide range of International Standards that already exist. International speakers from the USA, Germany and France will contribute to the meeting as well as UK users from the Pharmaceutical industry etc.

Please register your interest with pcig@outlook.com, or telephone Brian Miller or Sophie Lindsey on 01582 704807

Cost of attendance is £50. Program attached.

The meeting program is listed below

Robust Particle Characterisation, including International Standards

Date: Wednesday 4th April 2018

	Presenter	Affiliation	Presentation
9:30 to 9:45	Richard Holdich (Chair)	Loughborough Uni, UK	Introduction
9:45 to 10:15	Zoltan Nagy	Purdue University, USA	<i>Robust monitoring systems based on Raman spectroscopy for particle characterization</i>
10:15 to 10:45	Wolfgang Witt	Sympatec, Germany	<i>International Standards for Particle Size and Shape Analysis</i>
10:45 to 11:15	coffee		
11:15 to 11:45	Steve Ward Smith	Malvern, UK	<i>The principles of setting up robust particle characterisation methods using a quality by design approach</i>
11:45 to 12:15	Jo Rowland	GSK, UK	<i>Tools for a robust laser diffraction method</i>
12:15 to 13:15	lunch		
13:15 to 13:30	Maurice Wedd (Chair)		Introduction and Reflection
13:30 to 14:00	Alan Rawle	Malvern, USA	<i>Standards: a US perspective</i>
14:00 to 14:30	Richard Tweedie	UK	<i>Robust on-line sensors for particle characterization</i>
14:30 to 14:45	tea		
14:45 to 15:15	Graham Rideal	Whitehouse Scientific	<i>Validating an image analyser to prove traceability back to the international standard metre</i>
15:15 to 15:45	Escubed	UK	<i>TBC</i>
15:45 to 16:15	Peter Høghøj	Xenocs SAS	<i>High resolution measurement of size-distributions of nano-particles according to ISO 17867</i>
16:15 to 16:30	Peter Laggner	RCPE Graz	<i>Inner Surface and Density Fluctuation in Powders by SAXS</i>
	Meeting close		